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(54) **GAIN CALIBRATION WITH QUANTIZER
OFFSET SETTINGS**

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(57) **ABSTRACT**

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Methods and apparatus for calibrating a gain for a circuit block are disclosed. An example method includes receiving a plurality of quantizer offsets, where the plurality of quantizer offsets represent calibration data for a quantizer configured to quantize an output of the circuit block, determining one or more differences based on one or more first quantizer offsets of the plurality of quantizer offsets and on one or more second quantizer offsets of the plurality of quantizer offsets, and determining an incremental change in a gain associated with the circuit block based on the one or more differences.

